

METHOD AND APPARATUS OF DETERMINING DEFECT-FREE

SEMICONDUCTOR INTEGRATED CIRCUIT

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ABSTRACT OF THE DISCLOSURE

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A method and apparatus of determining a defect-free semiconductor integrated circuit such as CMOS IC able to determine a defect-free device regardless of the existence of a circuit leakage current, including a step of selecting defect-free CMOS integrated circuit from a group of CMOS integrated circuits a step of successively inspecting the test IC and reference defect-free IC for resemblance of features of quiescent power supply currents (QPSCs), and a step of determining if there is resemblance between the features test IC is defect-free.